

## 測試報告 Test Report

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億光電子工業股份有限公司

EVERLIGHT ELECTRONICS CO., LTD.

台北縣土城市中央路三段76巷25號

NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIPEI, TAIWAN, R. O. C.



以下測試樣品係由客戶送樣，且由客戶聲稱並經客戶確認如下 (The following samples was/were submitted and identified by/on behalf of the client as):

BASIC INFORMATION	
Type of Product	PHOTO COUPLER DIP 類-無鹵素機種 (EL81x-G, EL82x-G, 4Nxx-G, CNY17-x-G, CNY17F-x-G, H11x-G, EL30xx-G, 6Nxxx-G, TIL1xx-G, MCT2x-G)
Supplier Company Name	EVERLIGHT
Address	NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIWAN, R. O. C.
Tel/Fax/Email	TEL:886-2-267-2000 EXT:1203 FAX:886-2-267-9948 E-MAIL: meelin@everlight.com
Contact Person	LIN HSIAO HUA
EVERLIGHT REPORT NO	EVERLIGHT-EL81x-G, EL82x-G, 4Nxx-G, CNY17-x-G, CNY17F-x-G, H11x-G, EL30xx-G, 6Nxxx-G, TIL1xx-G, MCT2x-G-SGS-08/03/2010
PRODUCT INFORMATION	
Product/component Sample description	ISOLATION UNIT
Quantity (numbers or weight)	0.2282g
Supplier P/N	EL81x-G, EL82x-G, 4Nxx-G, CNY17-x-G, CNY17F-x-G, H11x-G, EL30xx-G, 6Nxxx-G, TIL1xx-G, MCT2x-G
Product Lot No	1X-673
Country of Origin	TAIWAN
TEST INFORMATION	
Digital Photo(s) of sample(s) after being prepared	JPG EMBEDDED IN EACH REPORT
Sample preparation	CUTTING
Test Method	Halogen-BS EN 14582
PQL and/or MDL	Halogen: 50 mg/kg
Name of Analyzer	Halogen: Rita Chen

收件日期(Sample Receiving Date) : 2010/02/26  
 測試期間(Testing Period) : 2010/02/26 TO 2010/03/08

=====  
 測試結果(Test Results) : 請見下一頁 (Please refer to next pages).

*Shin-Jyh Chen*

**Shin-jyh Chen / Asst. Manager**  
**Signed for and on behalf of**  
**SGS TAIWAN LTD.**  
**Chemical Laboratory - Taipei**

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### 測試結果(Test Results)

測試部位(PARTNAME)NO.1 : 本體 (BODY)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				NO.1
鹵素 / Halogen				
鹵素 (氟) / Halogen-Fluorine (F) (CAS No.: 014762-94-8)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素 (氯) / Halogen-Chlorine (Cl) (CAS No.: 022537-15-1)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	161
鹵素 (溴) / Halogen-Bromine (Br) (CAS No.: 010097-32-2)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素 (碘) / Halogen-Iodine (I) (CAS No.: 014362-44-8)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.

### 備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 1000ppm
2. n.d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)

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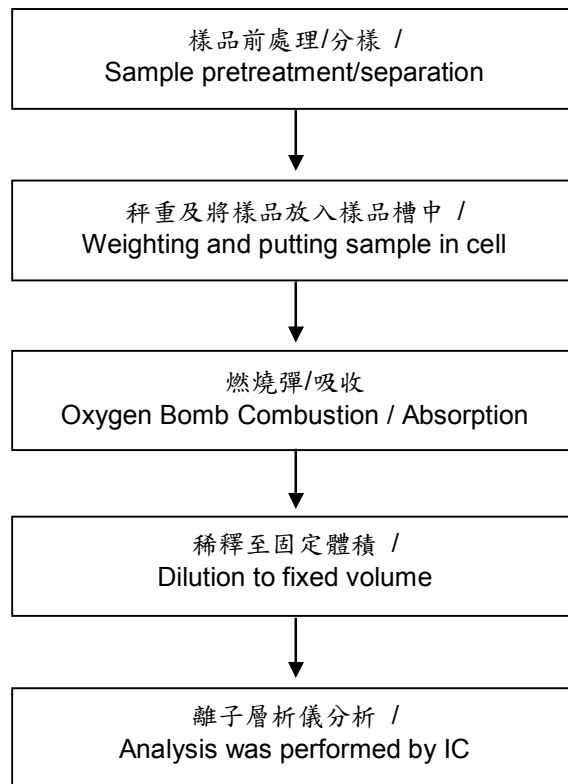
台北縣土城市中央路三段76巷25號

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### 鹵素分析流程圖 / Analytical flow chart of halogen content

- 1) 測試人員：陳恩臻 / Name of the person who made measurement: Rita Chen
- 2) 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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\*\* 報告結尾 (End of Report) \*\*

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